


<b>Search Notes</b>  	<b>Application/Control No.</b>  10582930	<b>Applicant(s)/Patent Under Reexamination</b>  MEIER ET AL.
	<b>Examiner</b>  NATHANIEL WIEHE	<b>Art Unit</b>  3745

SEARCHED			
Class	Subclass	Date	Examiner
415	173.1,173.4,173.5,174.4,174.5,200	8/12/2008	NEW

SEARCH NOTES		
Search Notes	Date	Examiner
415/173.1,173.4,173.5,174.4,174.5,200 Dwyane White	8/12/2008	NEW
Text Search (See EAST Search History)	8/12/2008	NEW
Palm Inventor Name Search	8/12/2008	NEW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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